

PLANAR MICROLENSES FOR SPAD SENSORS

ISSW2020 | June 8th, 2020



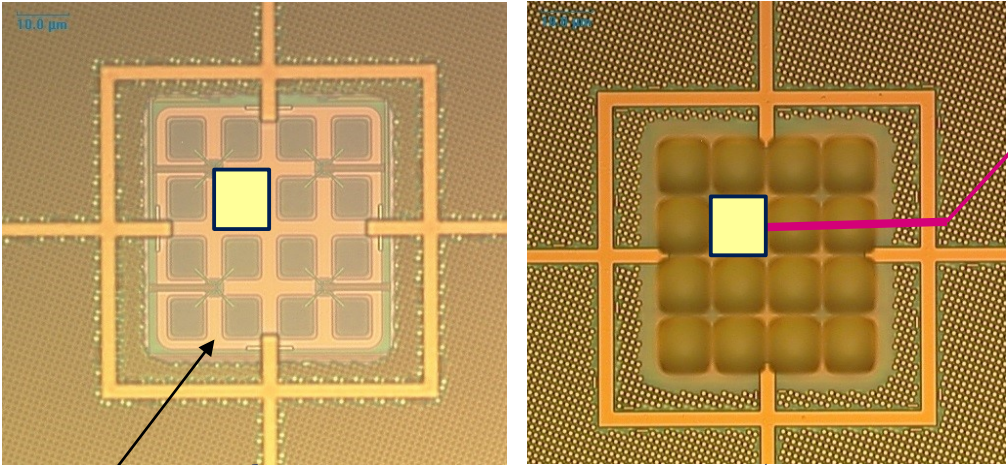
Norbert Moussy , Lucie DILHAN, Jérôme VAILLANT, Alain OSTROVSKY,
Lilian MASAROTTO, Céline PICHARD, Romain PAQUET

- **Introduction**
 - SPAD array and melted microlens
 - Towards planar microlenses
- **Planar microlenses**
 - Theory basics
 - Process
 - Simulations
 - Characterization results
- **Conclusion**

INTRODUCTION



- **SPAD array with standard melted microlens**
 - 4x4 SPADs pixels 10.18 μm pitch to form a macropixel
 - STMicroelectronics C40 CMOS technology

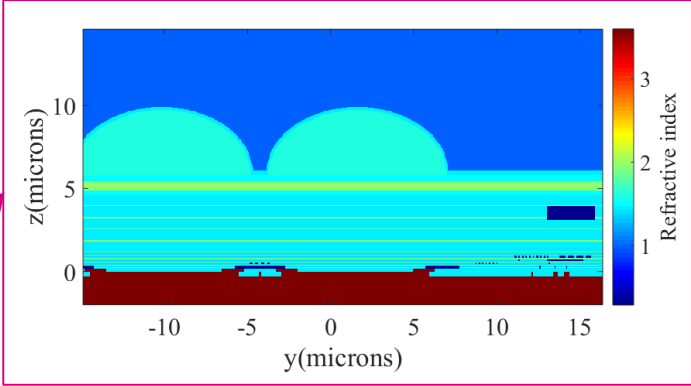
Macropixel without microlens ($ff_o \sim 40\%$) Macropixel with melted microlens



Metal shielding

Fill-factor +30% [2]

-  Light-collecting surface
-  Pixel surface



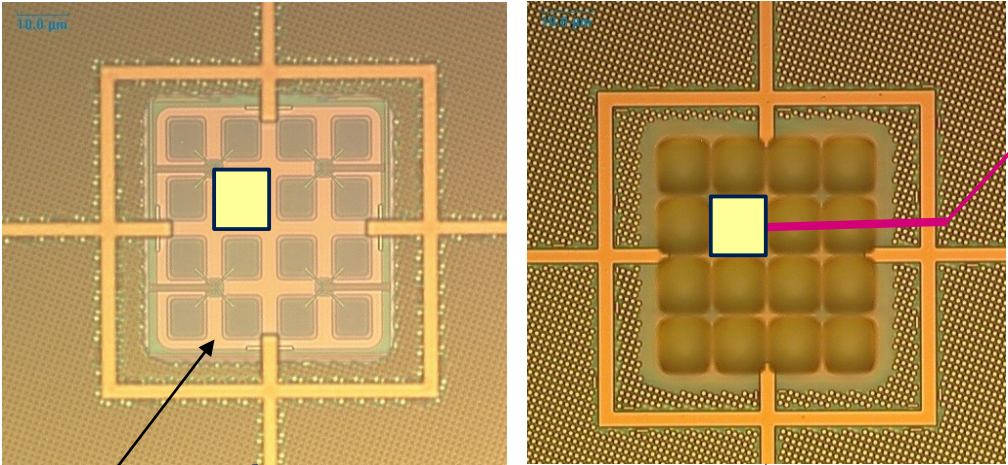
Cross-section of 2 SPAD pixels with melted microlens [3]

[1] G. Intermite et al, Enhancing the Fill-Factor of CMOS SPAD Arrays Using Microlens Integration, Proceedings of SPIE, Vol. 9504 (2015).
 [2] S. Pellegrini, International SPAD Sensor Workshop (2018).
 [3] High-Performance Nanophotonic Simulation Software, <http://www.lumerical.com/>.

INTRODUCTION

- SPAD array with standard melted microlens**
 - 4x4 SPADs pixels 10.18 μm pitch to form a macropixel
 - STMicroelectronics C40 CMOS technology

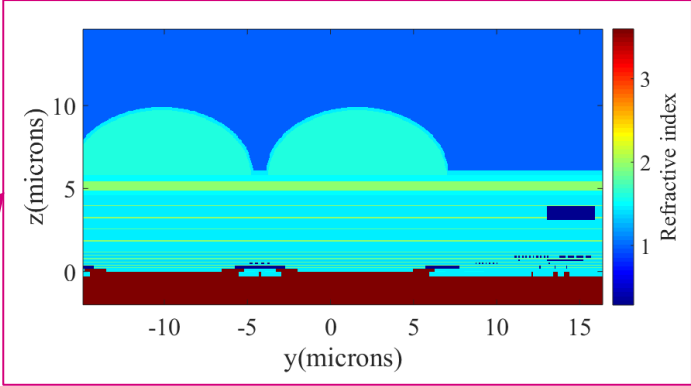
Macropixel without microlens ($ff_0 \sim 40\%$) Macropixel with melted microlens



Metal shielding

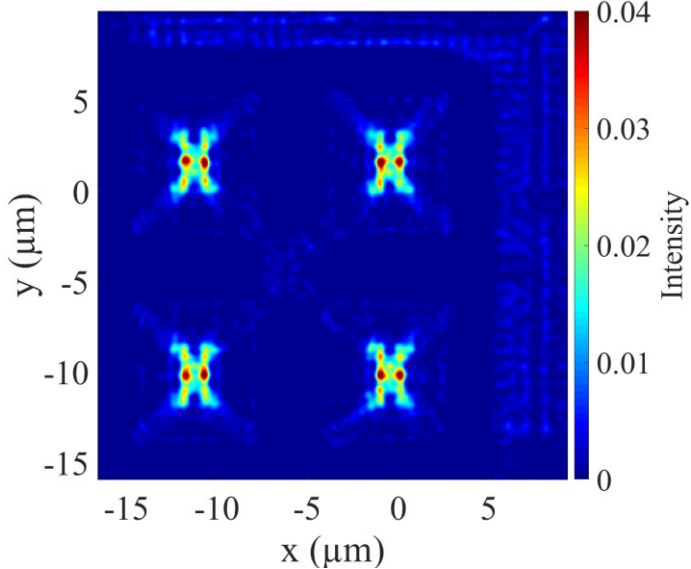
Fill-factor +30% [2]

- Light-collecting surface
- Pixel surface



Cross-section of 2 SPAD pixels with melted microlens [3]

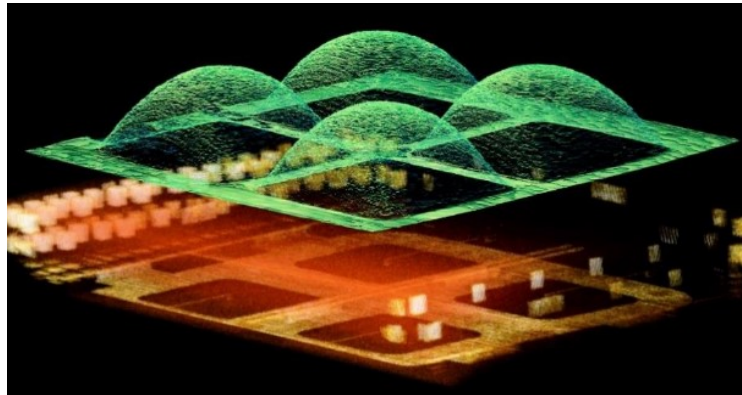
FDTD calculation of light intensity at Si entrance [3]



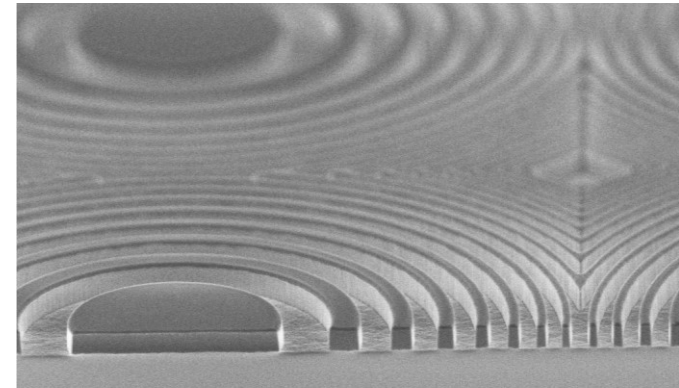
[1] G. Intermite et al, Enhancing the Fill-Factor of CMOS SPAD Arrays Using Microlens Integration, Proceedings of SPIE, Vol. 9504 (2015).
 [2] S. Pellegrini, International SPAD Sensor Workshop (2018).
 [3] High-Performance Nanophotonic Simulation Software, <http://www.lumerical.com/>.

TOWARD PLANAR MICROLENSSES

- Melted microlens
 - Adapted process for 10 μm pitch max
 - « Thick » layer (few μm) dedicated to large pitch
 - Topography, « dome » shape
 - Shape irregularity due to variability of reflow process
 - Delicate process with reliability concerns
 - Sensitive to temperature
- Planar microlens
 - Shaped by design (mask)
 - « Thin » layer ($<1 \mu\text{m}$)
 - Planar surface
 - Gapless possibilities
 - Classical lithography steps (litho-etch)
 - Materials robust to reliability testing

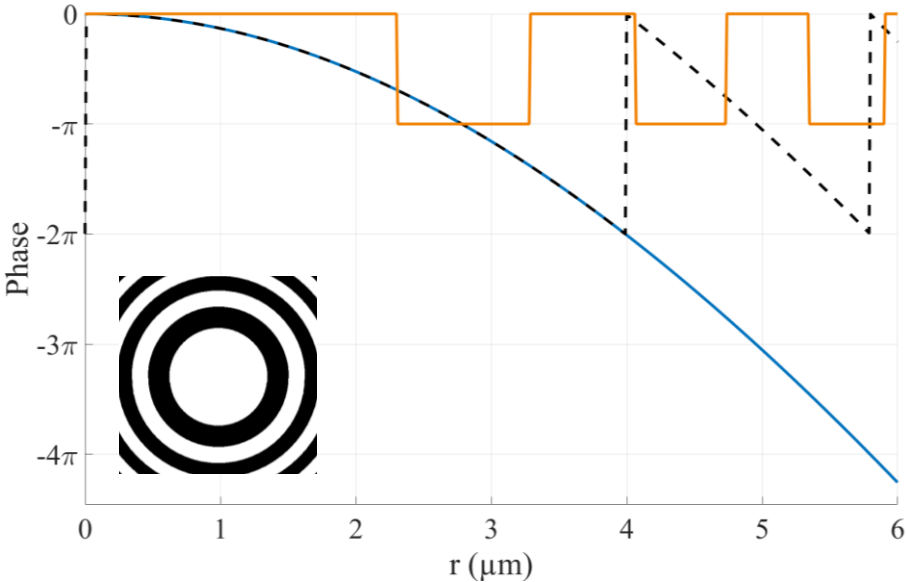


S. Pellegrini, ISSW2018

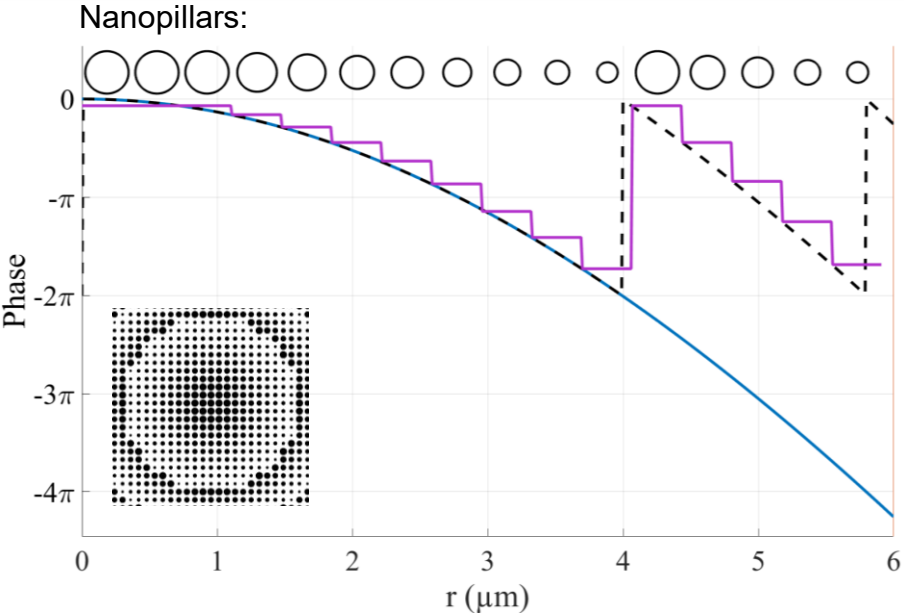


Fresnel Zone Plate

- Arbitrary profile
- - - Phase modulo 2π
- FZP phase profile
- Meta phase profile



Metamicrolens



With Plan convex profile

$f = 8 \mu\text{m}$
 $\lambda = 940 \text{ nm}$
 Normal incidence
 $n_{\text{spacer}} = 1,45$

Binary phase, $0 - \pi$
 Radius of the k_{th} ring:

$$R_k = \sqrt{\frac{k\lambda}{n} \left(f + \frac{k\lambda}{4n} \right)}$$

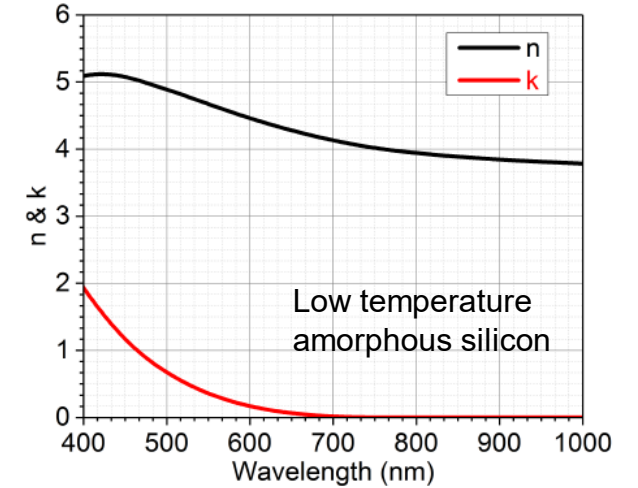
Phase gradient, $0 - 2\pi$
 Phase at position r :

$$\varphi(r) = \left[\frac{2\pi}{\lambda} \left(\sqrt{r^2 + f^2} - f \right) \right] \text{mod}(2\pi)$$

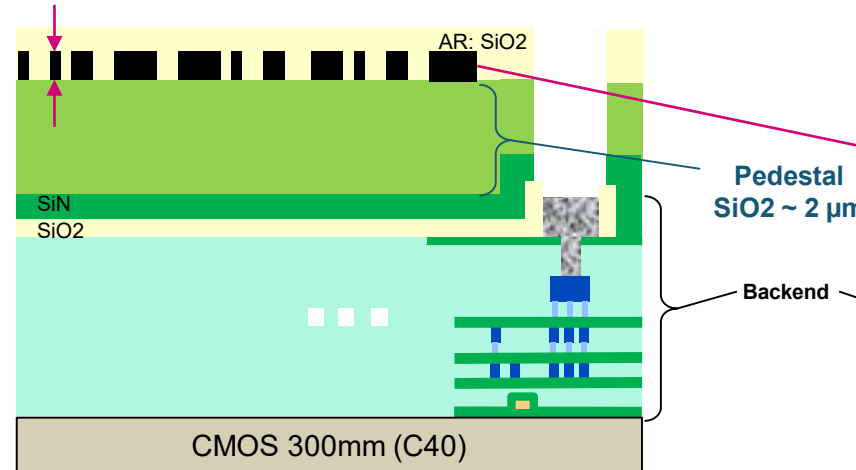
PROCESS

Process materials

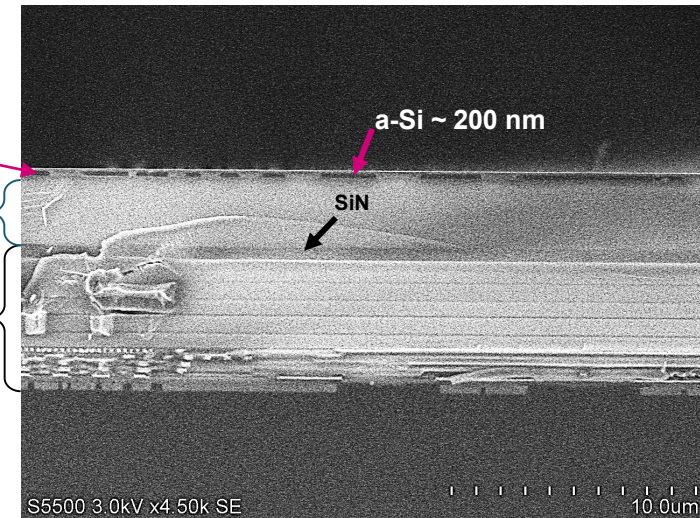
- Silicon oxide spacer (2 μm to 10 μm) adjusted to focal distance and pixel size.
- Amorphous silicon, high index (3.8) for phase shift transparent at $\lambda > 800 \text{ nm}$
- Stress minimization of the full stack (mainly aSi)
- Silicon oxide as antireflective coating
- Final planarisation



h = 200nm a-Si



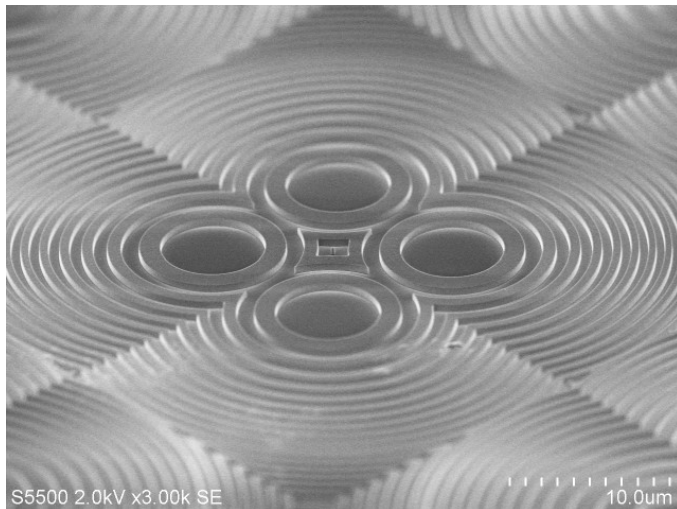
Process layout cross-section



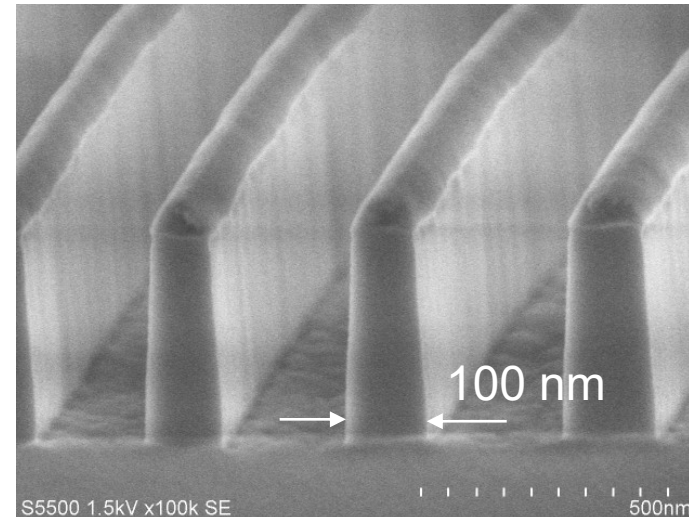
MEB cross-section

- **Patterning control**

- Deep UV scanner with optical proximity correction (OPC)
- Down to 100 nm structures, up to 500 nm tall
- (Quasi) Vertical etch optimization with resist and SiO₂ hard mask
- High aspect ratio filling with SiO₂ (Anti reflective coating)



Artistic view of Quad SPAD μ lenses



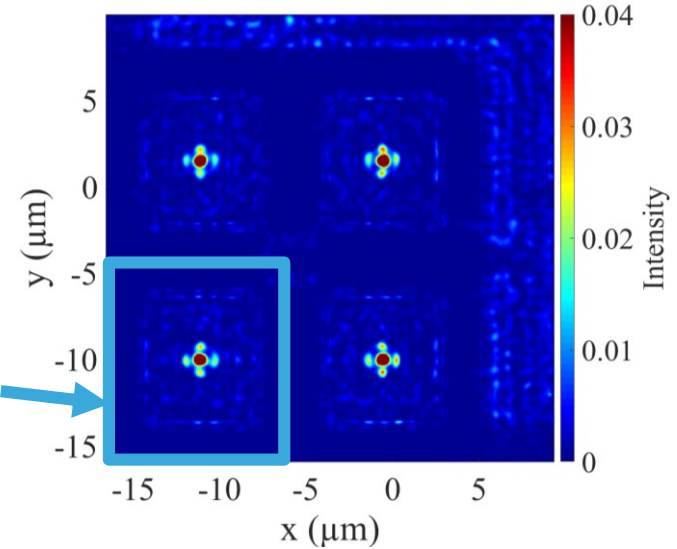
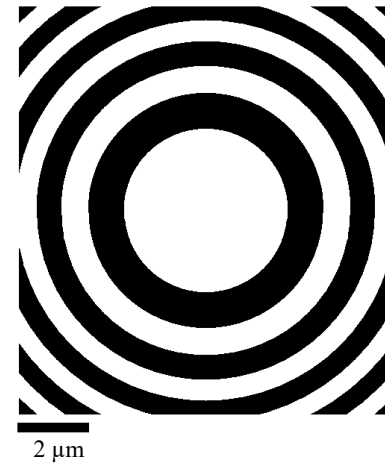
SEM cross section before resist mask removal

LAYOUT AND SIMULATION

- FZP microlens**

Only h, f optimization parameters with process constraints

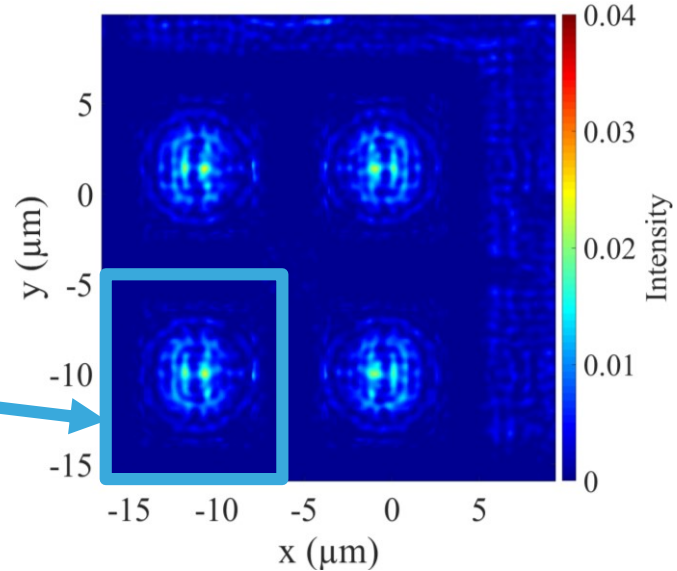
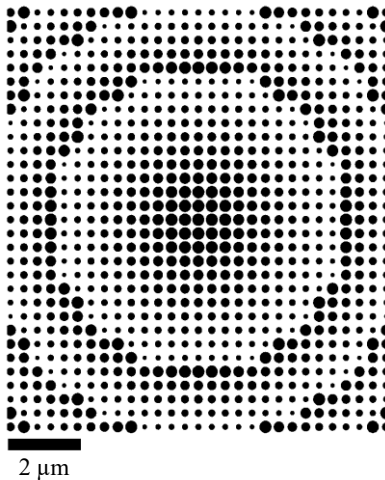
Key parameters:
 $f = 8 \mu\text{m}$
 $h = 200 \text{ nm}$
 $\text{AR} = 150 \text{ nm}$



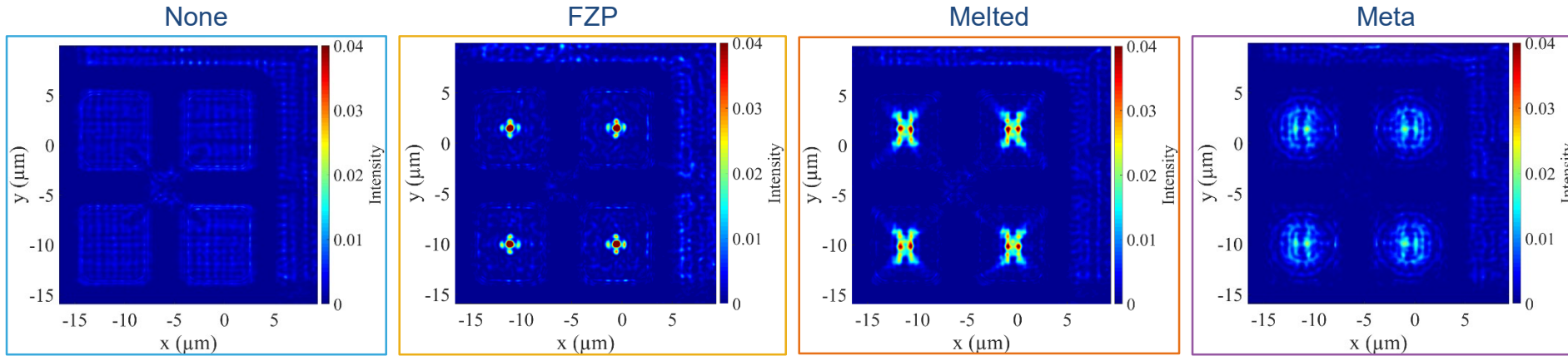
- Metamicrolens**

- Choice of pitch (process)
- Define library of pillars with 0 to 2π phase shift
- Optimization on h, f, pillars/pitch

Key parameters:
 $f = 8 \mu\text{m}$
 $h = 500 \text{ nm}$
 pitch = 370 nm
 Phase : 0 to 2π



SIMULATED PERFORMANCES

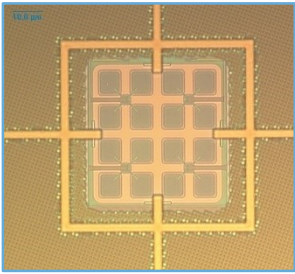
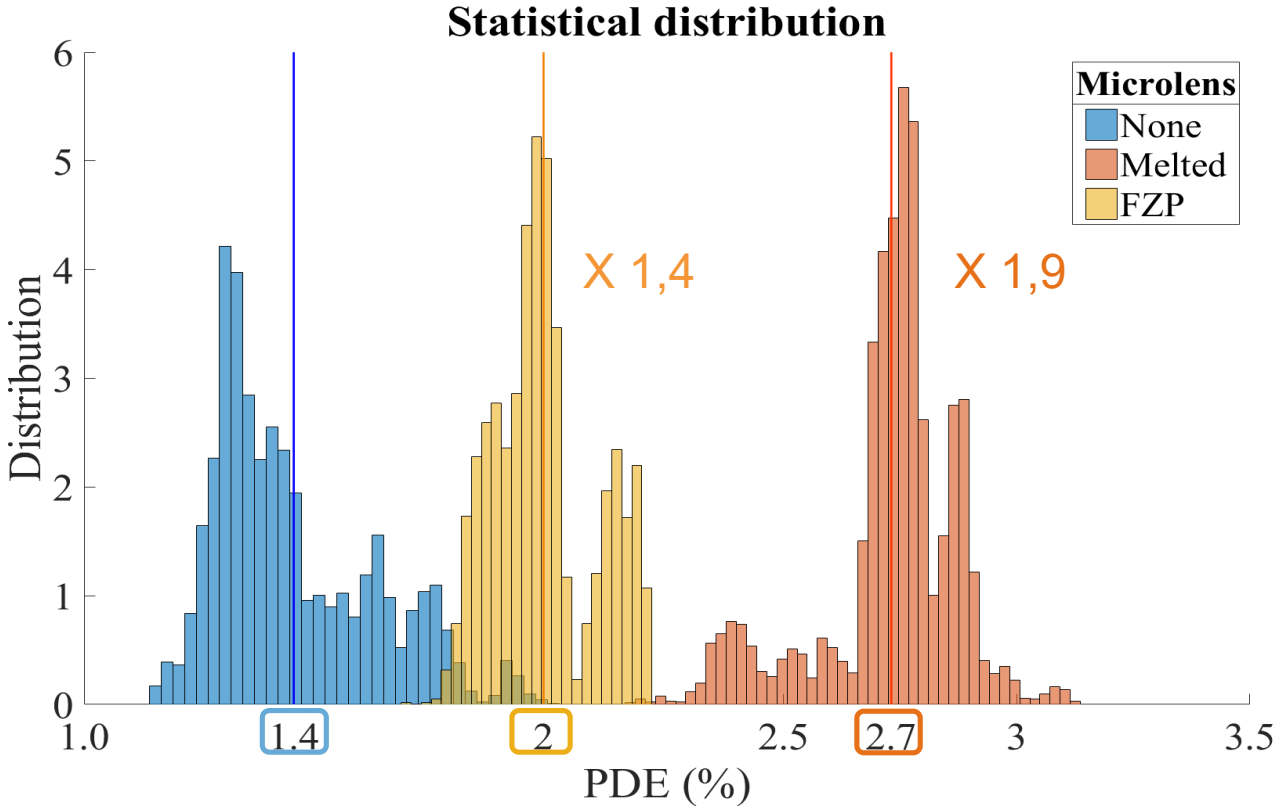


Microlens type	None	FZP	Melted	Meta
Simulated PDE (%)	2,2 ± 0,2	2,6 ± 0,1	3,4 ± 0,2	4,1 ± 0,1
Average gain	—	x 1,2	x 1,5	x1,8

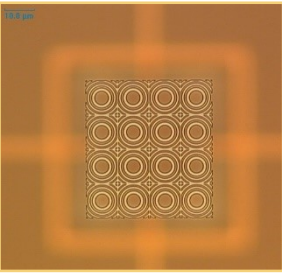
PDE: Photon Detection Efficiency on pixel pitch

$$\text{Maximum gain (ff}_O=40\%) = S_{\text{pixel}} / S_{\text{SPAD metal Shield}} = \mathbf{x 2,5}$$

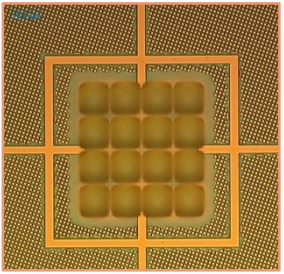
CHARACTERIZATION RESULTS



No microlens

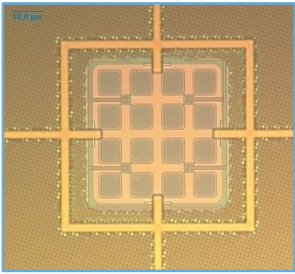
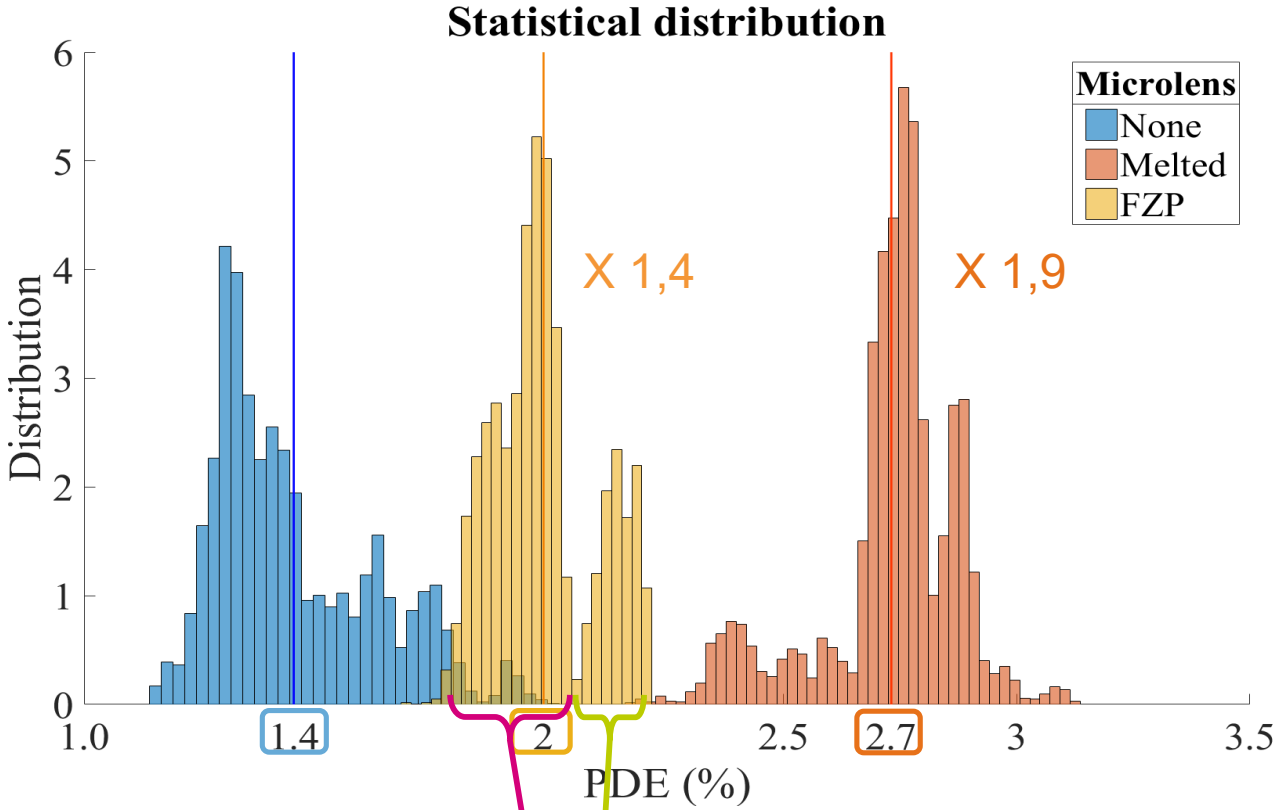


FZP microlens

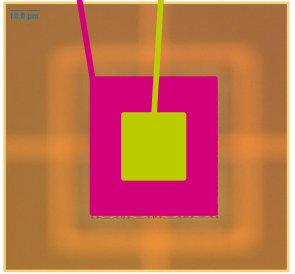


Melted microlens

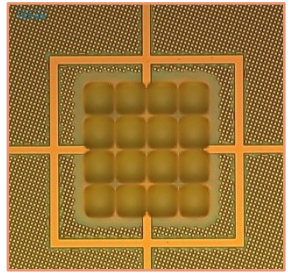
CHARACTERIZATION RESULTS



No microlens



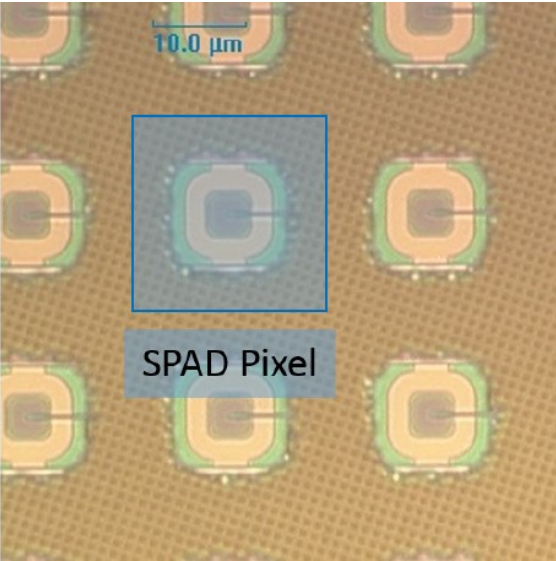
FZP microlens



Melted microlens

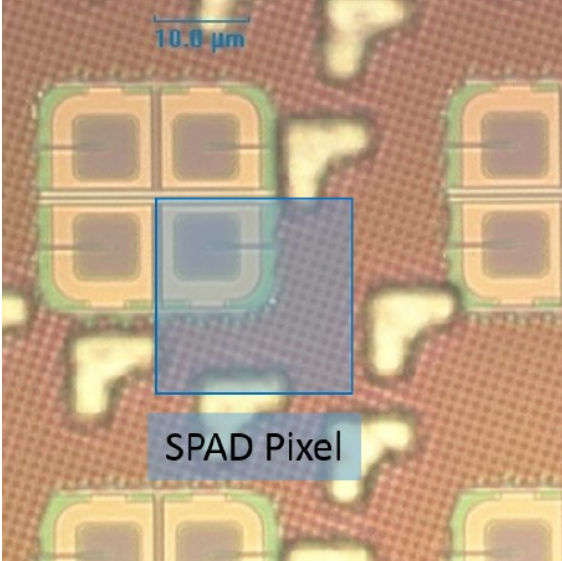
PREVIOUS RESULTS ON LARGE PITCH ARRAYS

- Tested SPAD arrays
 - Isolated SPADs 21.6 μm pitch and Quad SPAD (2x2 SPAD) pixels
 - Large Microlens on total pitch not available in reflow process
 - Off axis optical center



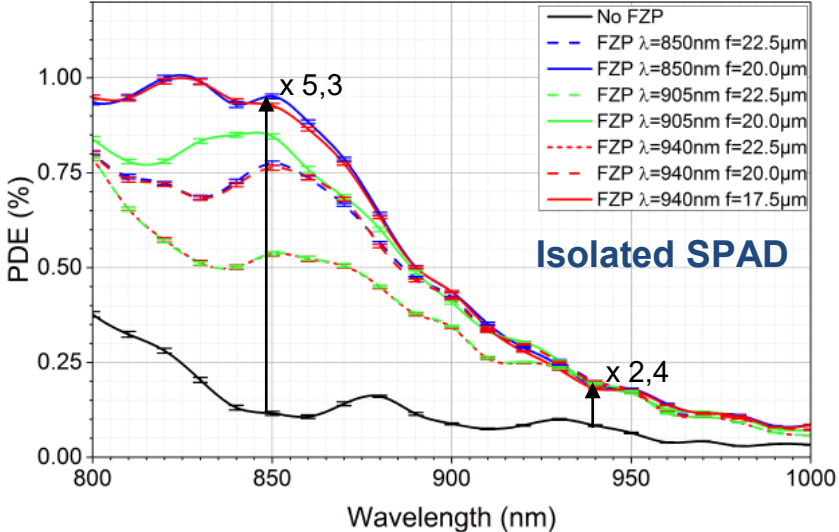
Isolated SPAD

21.6 μm pitch, 5% ff_0
4.7 μm metal shield opening



Quad SPAD

2x2 SPAD macropixel
21.6 μm pitch, 12% ff_0
7.5 μm metal shield opening



FZP μlens	Gain @ 940 nm	$S_{\text{pixel}}^* / S_{\text{SPAD}}$
Isolated SPAD	$x 2,4 \pm 0,1$	21
Quad SPAD	$x 1,7 \pm 0,1$	8

*Presence of metals in light path

CONCLUSION

- **Planar microlens**

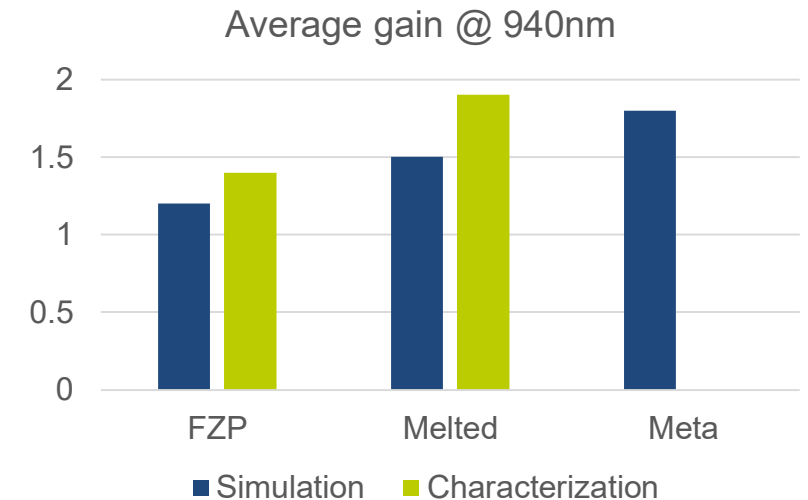
- Some process and stability advantages
- Predictive simulations : Require a tight description of stack materials and layout (f/2 aperture, neighborhood to be included)
- Arbitrary lens shape
- Low limit $\sim 5 \mu\text{m}$ pitch, large pitch must be confirmed
- 940 nm much more difficult than 850 nm wavelength

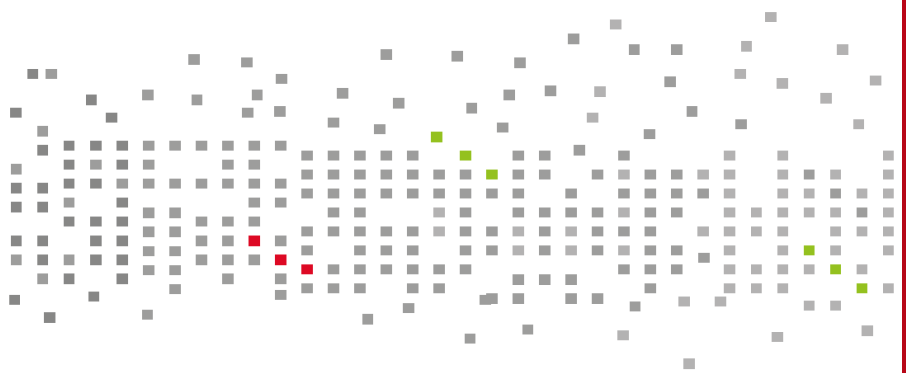
- **FZP microlens**

- Gain lower than melted microlens
- Process successfully developed

- **Metamicrolens**

- Gain should be close to melted microlens
- Process under development





Leti, technology research institute
Commissariat à l'énergie atomique et aux énergies alternatives
Minatéc Campus | 17 avenue des Martyrs | 38054 Grenoble Cedex | France
www.leti-cea.com

